

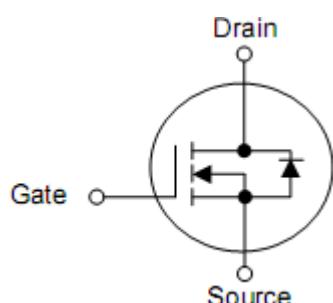
1. Features

- $R_{DS(ON)}=2.0\text{m}\Omega(\text{typ.}) @ V_{GS}=10\text{V}$
- Very Low On-resistance $R_{DS(ON)}$
- Low C_{RSS}
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability

2. Applications

- PWM Application
- Power Management
- Load switch

3. Symbol



Pin	Function
1	Gate
2	Drain
3	Source

4. Ordering Information

Part Number	Package	Brand
KNP2803S	TO-220S	KIA

5. Absolute maximum ratings

$T_C=25^\circ\text{C}$ unless otherwise noted

Parameter	Symbol	Rating	Units
Drain-source voltage	V_{DSS}	30	V
Continuous drain current	I_D	150	A
	I_D	90	A
Pulsed drain current -Pulsed ¹⁾	I_{DM}	560	A
Gate-source voltage	V_{GS}	± 20	V
Single pulse avalanche energy ²⁾	E_{AS}	552	mJ
Power dissipation($T_C=25^\circ\text{C}$)	P_D	107	W
Operating junction and storage temperature range	T_J, T_{STG}	-55 to 175	$^\circ\text{C}$
Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds	T_L	300	$^\circ\text{C}$

*Drain current limited by maximum junction temperature.

6. Thermal characteristics

Parameter	Symbol	Rating	Unit
Thermal resistance junction-case	$R_{\theta JC}$	1.4	$^\circ\text{C}/\text{W}$

7. Electrical characteristics

($T_C=25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Units
Drain-source breakdown voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	30	-	-	V
Drain-source leakage current	I_{DSS}	$V_{\text{DS}}=30\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
		$V_{\text{DS}}=24\text{V}, T_C=125^\circ\text{C}$	-	-	10	μA
Gate-source forward leakage	I_{GSS}	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Gate threshold voltage	$V_{\text{GS(TH)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	1.0	1.5	2.5	V
Drain-source on-resistance	$R_{\text{DS(on)}}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=30\text{A}$	-	2.0	3.0	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}, I_{\text{D}}=20\text{A}$	-	3.3	5.5	$\text{m}\Omega$
Input capacitance	C_{iss}	$V_{\text{DS}}=20\text{V}, V_{\text{GS}}=0\text{V}$ $f=1\text{MHz}$	-	4555	-	pF
Output capacitance	C_{oss}		-	476	-	pF
Reverse transfer capacitance	C_{rss}		-	451	-	pF
Turn-on delay time	$t_{\text{d(on)}}$	$V_{\text{GS}}=10\text{V}, V_{\text{DS}}=15\text{V},$ $R_G=3\Omega, I_{\text{D}}=30\text{A}^3)$	-	25	-	ns
Rise time	t_r		-	23	-	ns
Turn-off delay time	$t_{\text{d(off)}}$		-	90	-	ns
Fall time	t_f		-	38	-	ns
Total gate charge(10V)	Q_g	$V_{\text{DS}}=15\text{V}, I_{\text{D}}=40\text{A}$ $V_{\text{GS}}=10\text{V}^3)$	-	92	-	nC
Gate-source charge	Q_{gs}		-	30	-	nC
Gate-drain charge	Q_{gd}		-	38	-	nC
Maximum Continuous Drain-Source Diode Forward Current	I_s	—	-	-	150	A
Maximum Pulsed Drain-Source Diode Forward Current	I_{SM}	—	-	-	560	A
Drain to Source Diode Forward Voltage	V_{SD}	$V_{\text{GS}}=0\text{V}, I_{\text{SD}}=30\text{A},$ $T_J=25^\circ\text{C}$	-	-	1.2	VS
Body Diode Reverse Recovery Time	t_{rr}	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}$	-	42	-	nS
Body Diode Reverse Recovery Charge	Q_{rr}		-	39	-	nC

Note:

1) Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature

2) EAS condition: $T_J=25^\circ\text{C}, V_{\text{DD}}=15\text{V}, V_{\text{G}}=10\text{V}, R_G=25\Omega, L=0.5\text{mH}$.

3) Pulse Test: Pulse Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 0.5\%$

8. Typical operating characteristics

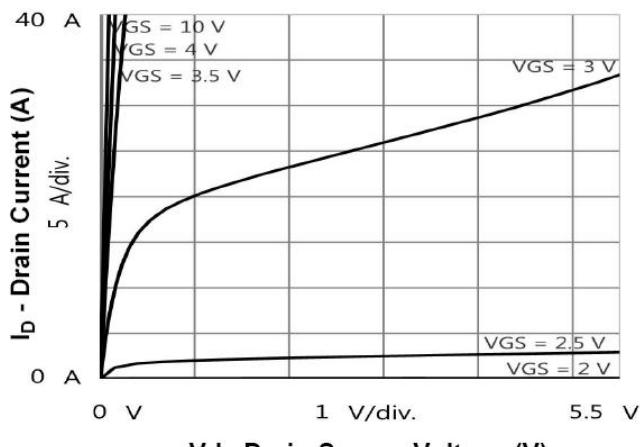


Figure 1. On-Region Characteristics

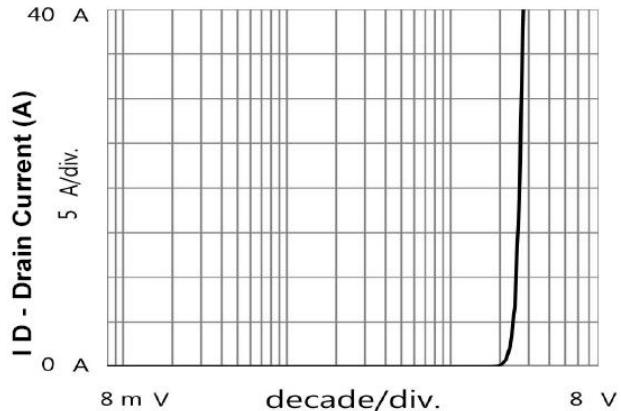
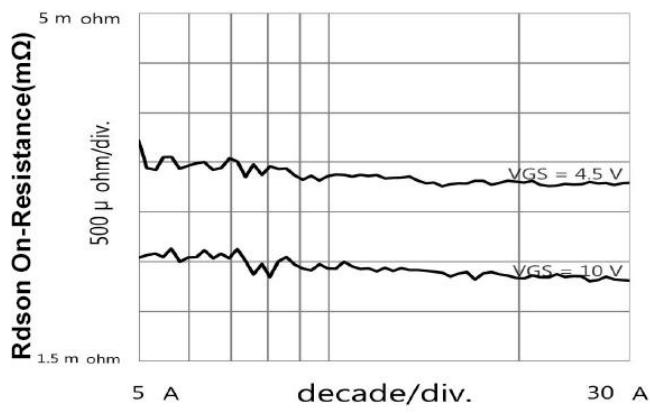
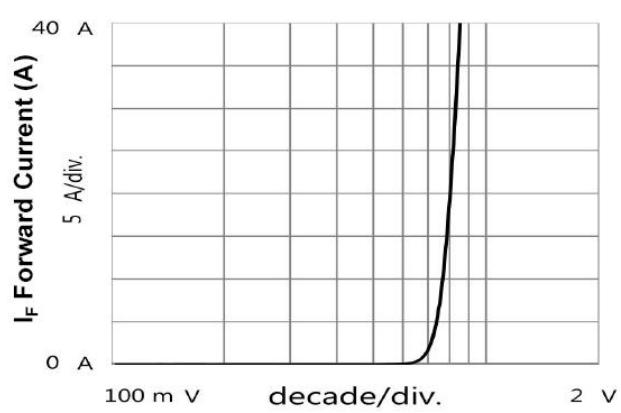


Figure 2. Transfer Characteristics



I D - Drain Current (A)

Figure 3. On-Resistance Variation vs Drain Current and Gate Voltage



V F ,Forward Voltage [V]

Figure 4. Body Diode Forward Voltage Variation with Source Current

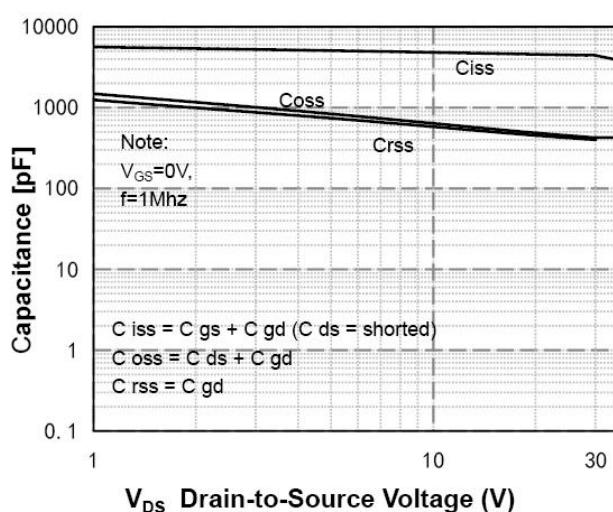


Figure 5. Capacitance Characteristics

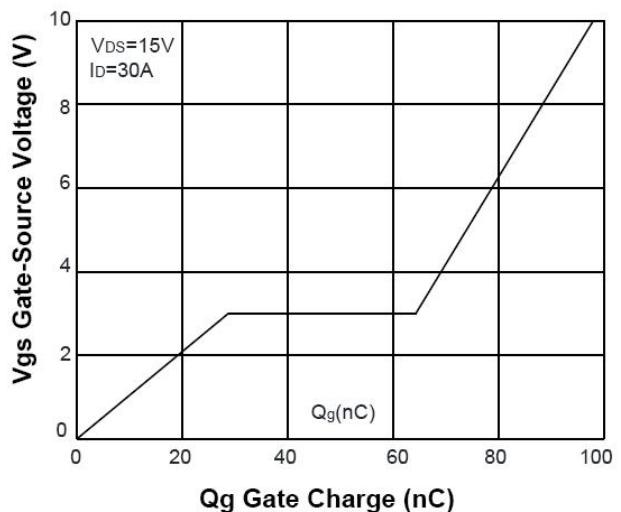
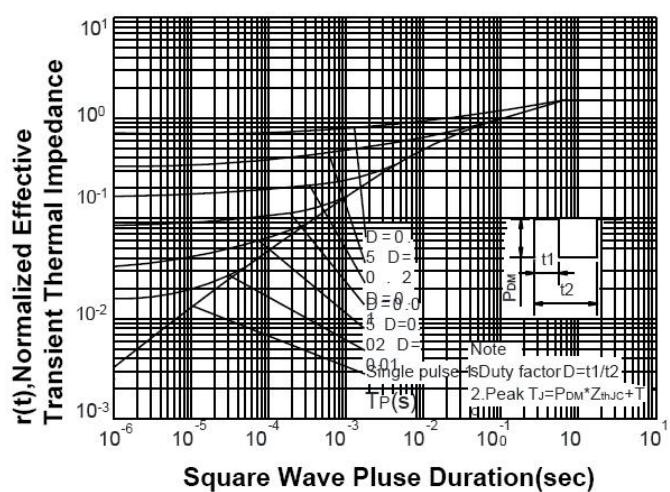
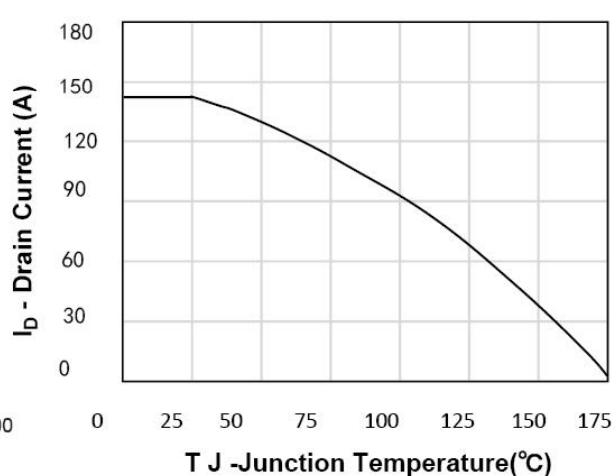
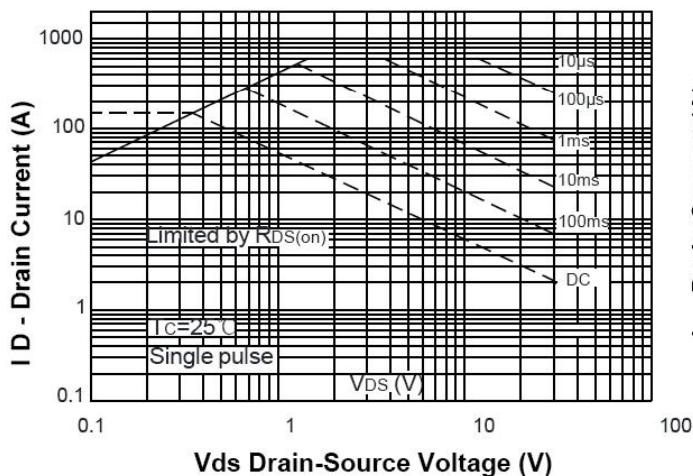
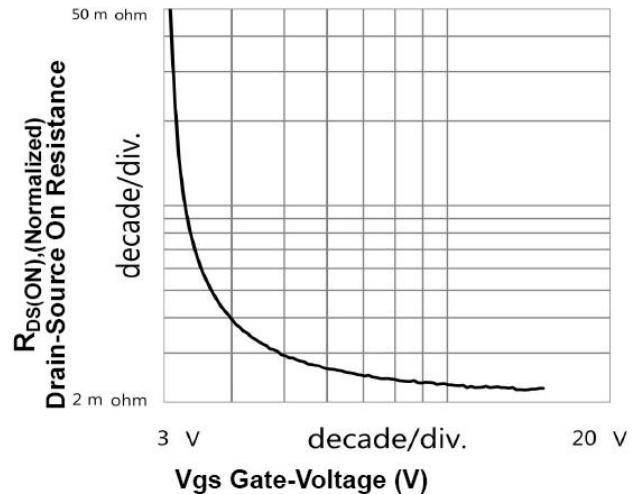
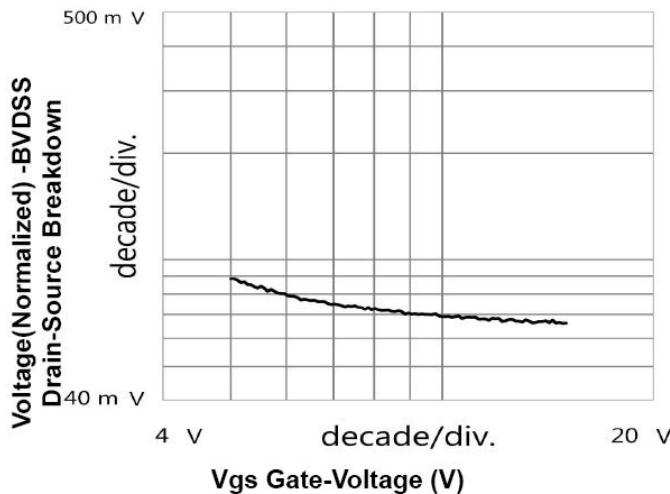
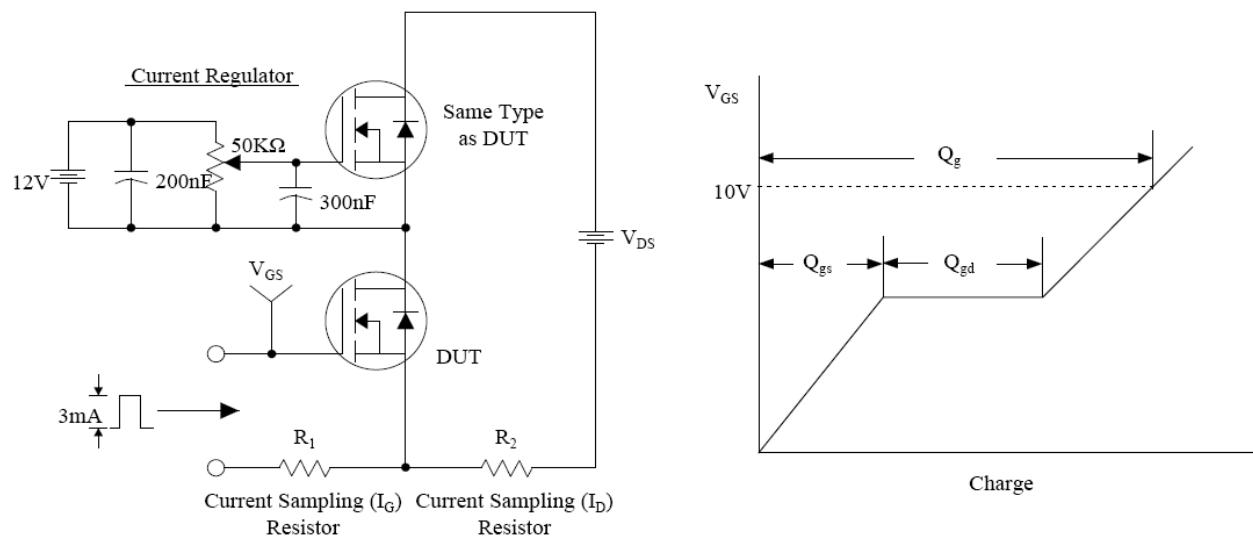


Figure 6. Gate Charge Characteristics

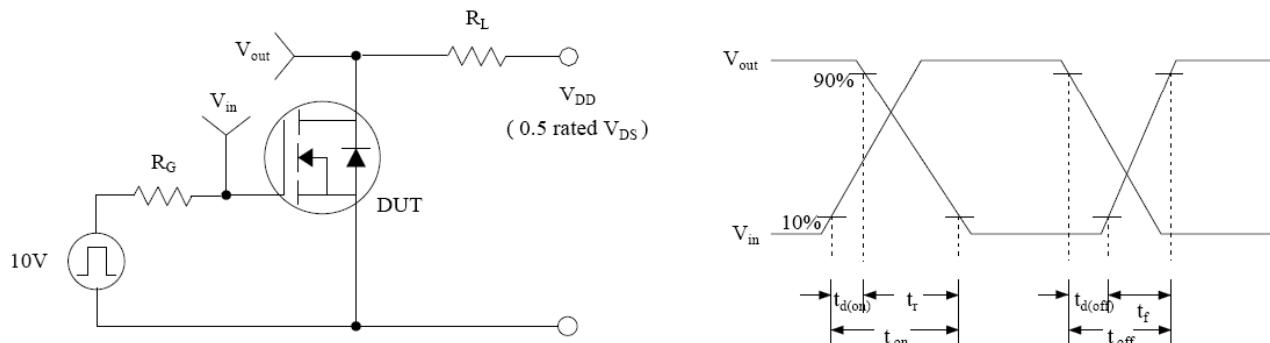


9. Test Circuits and Waveforms

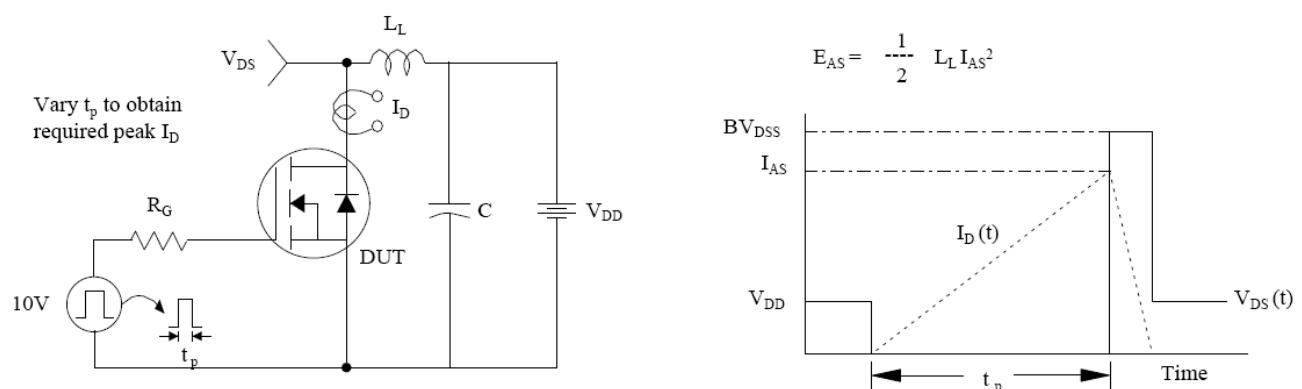
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms



Peak Diode Recovery dv/dt Test Circuit & Waveforms

